

International **IR** Rectifier

PD - 97284A

IRLR3114ZPbF IRLU3114ZPbF

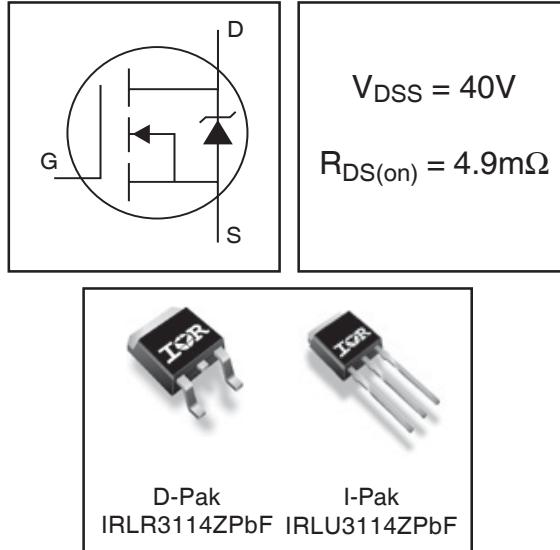
Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to T_{jmax}
- Logic Level

Description

This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

HEXFET® Power MOSFET



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	130	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Silicon Limited)	89	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Package Limited)	42	
I_{DM}	Pulsed Drain Current ①	500	
$P_D @ T_C = 25^\circ C$	Power Dissipation	140	W
	Linear Derating Factor	0.95	W/ $^\circ C$
V_{GS}	Gate-to-Source Voltage	± 16	V
E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ②	130	mJ
E_{AS} (Tested)	Single Pulse Avalanche Energy Tested Value ③	260	
I_{AR}	Avalanche Current ④	See Fig.12a, 12b, 15, 16	A
E_{AR}	Repetitive Avalanche Energy ⑤		mJ
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	$^\circ C$
	Reflow Soldering Temperature, for 10 seconds	300	
	Mounting Torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ⑥	—	1.05	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient (PCB mount) ⑦⑧	—	40	
$R_{\theta JA}$	Junction-to-Ambient ⑨	—	110	

HEXFET® is a registered trademark of International Rectifier.

www.irf.com

1

10/01/10

IRLR/U3114ZPbF

International
Rectifier

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	40	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.032	—	$\text{V}/^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	3.9	4.9	$\text{m}\Omega$	$V_{GS} = 10\text{V}, I_D = 42\text{A}$ ③
		—	5.2	6.5		$V_{GS} = 4.5\text{V}, I_D = 42\text{A}$ ③
$V_{GS(\text{th})}$	Gate Threshold Voltage	1.0	—	2.5	V	$V_{DS} = V_{GS}, I_D = 100\mu\text{A}$
g_{fs}	Forward Transconductance	98	—	—	S	$V_{DS} = 10\text{V}, I_D = 42\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 16\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -16\text{V}$
Q_g	Total Gate Charge	—	40	56	nC	$I_D = 42\text{A}$
Q_{gs}	Gate-to-Source Charge	—	12	—		$V_{DS} = 20\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	18	—		$V_{GS} = 4.5\text{V}$ ③
$t_{d(on)}$	Turn-On Delay Time	—	25	—	ns	$V_{DD} = 20\text{V}$
t_r	Rise Time	—	140	—		$I_D = 42\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	33	—		$R_G = 3.7\Omega$
t_f	Fall Time	—	50	—		$V_{GS} = 4.5\text{V}$ ③
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package
L_s	Internal Source Inductance	—	7.5	—		and center of die contact
C_{iss}	Input Capacitance	—	3810	—	pF	$V_{GS} = 0\text{V}$
C_{oss}	Output Capacitance	—	650	—		$V_{DS} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	350	—		$f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	2390	—		$V_{GS} = 0\text{V}, V_{DS} = 1.0\text{V}, f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	580	—		$V_{GS} = 0\text{V}, V_{DS} = 32\text{V}, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	820	—		$V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 32\text{V}$ ④

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	130	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	500		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 42\text{A}, V_{GS} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	30	45	ns	$T_J = 25^\circ\text{C}, I_F = 42\text{A}, V_{DD} = 20\text{V}$
Q_{rr}	Reverse Recovery Charge	—	27	41	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

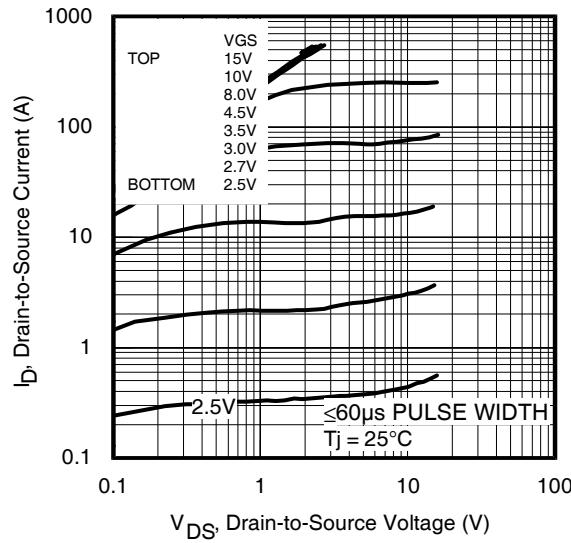


Fig 1. Typical Output Characteristics

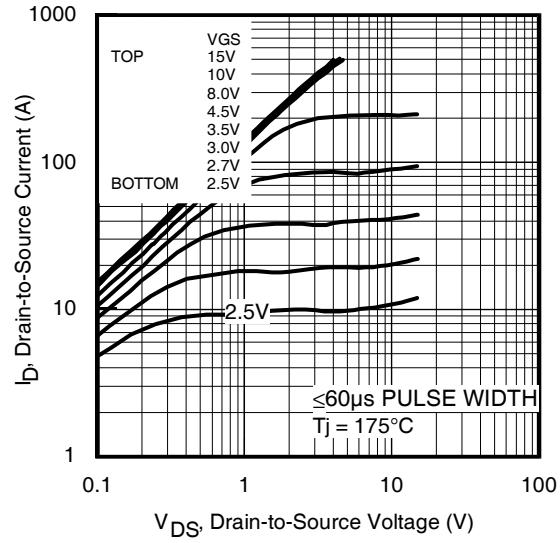


Fig 2. Typical Output Characteristics

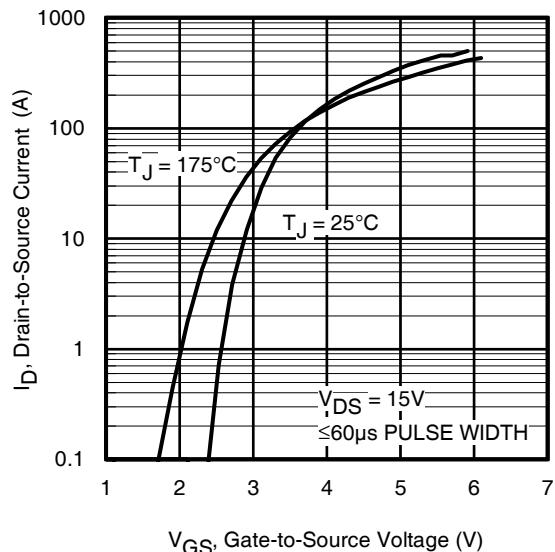


Fig 3. Typical Transfer Characteristics

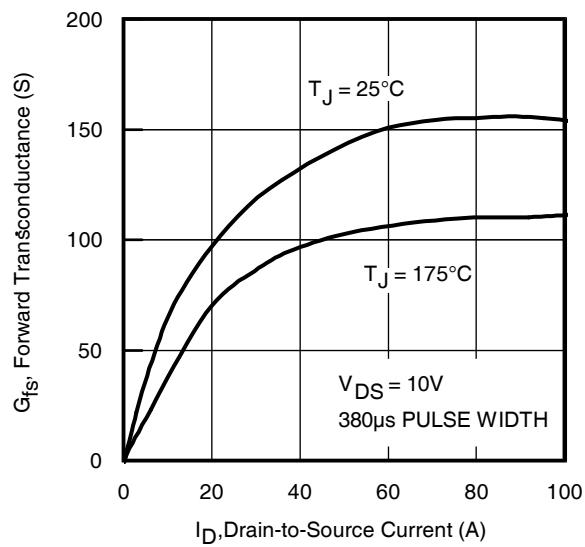


Fig 4. Typical Forward Transconductance
vs. Drain Current

IRLR/U3114ZPbF

International
IR Rectifier

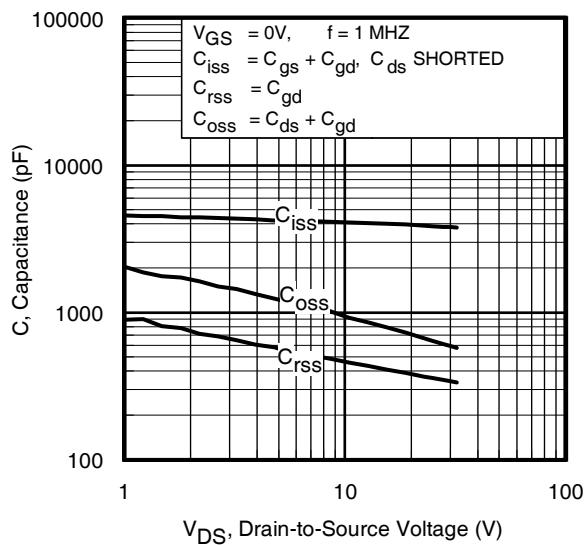


Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

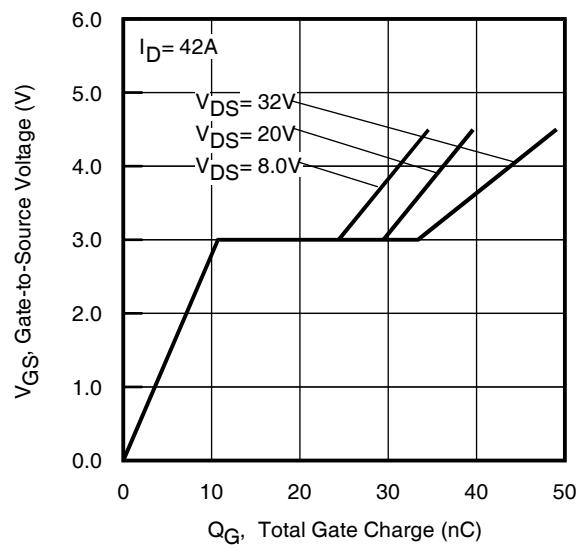


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

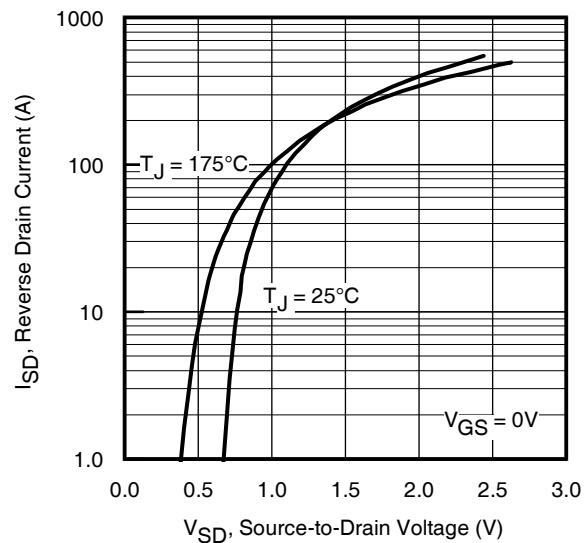


Fig 7. Typical Source-Drain Diode
Forward Voltage

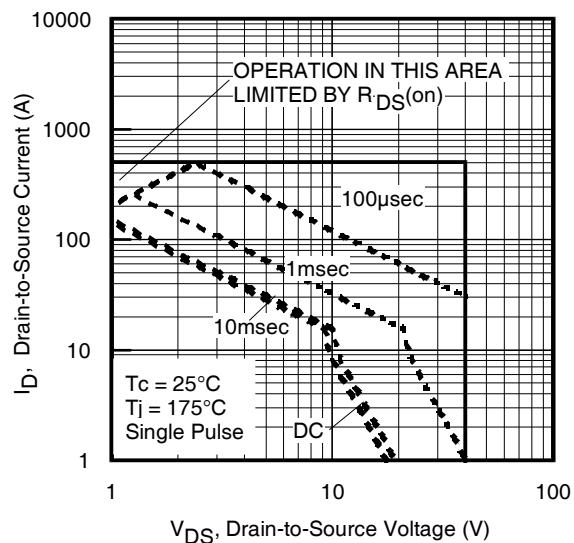


Fig 8. Maximum Safe Operating Area

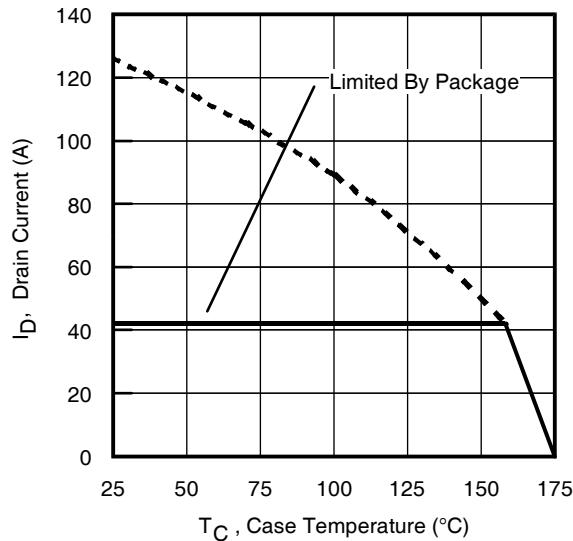


Fig 9. Maximum Drain Current vs.
Case Temperature

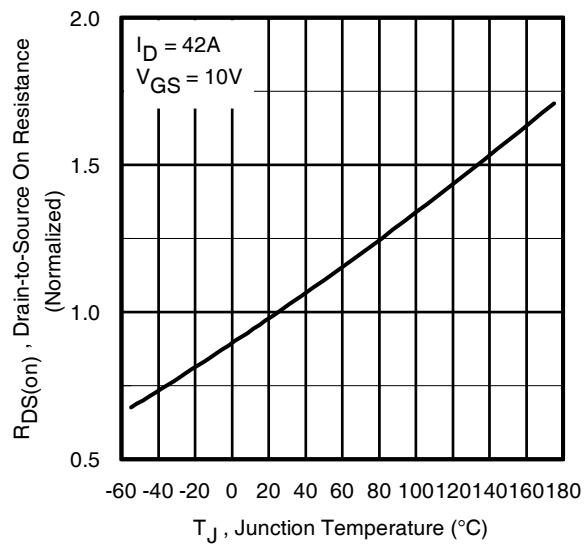


Fig 10. Normalized On-Resistance
vs. Temperature

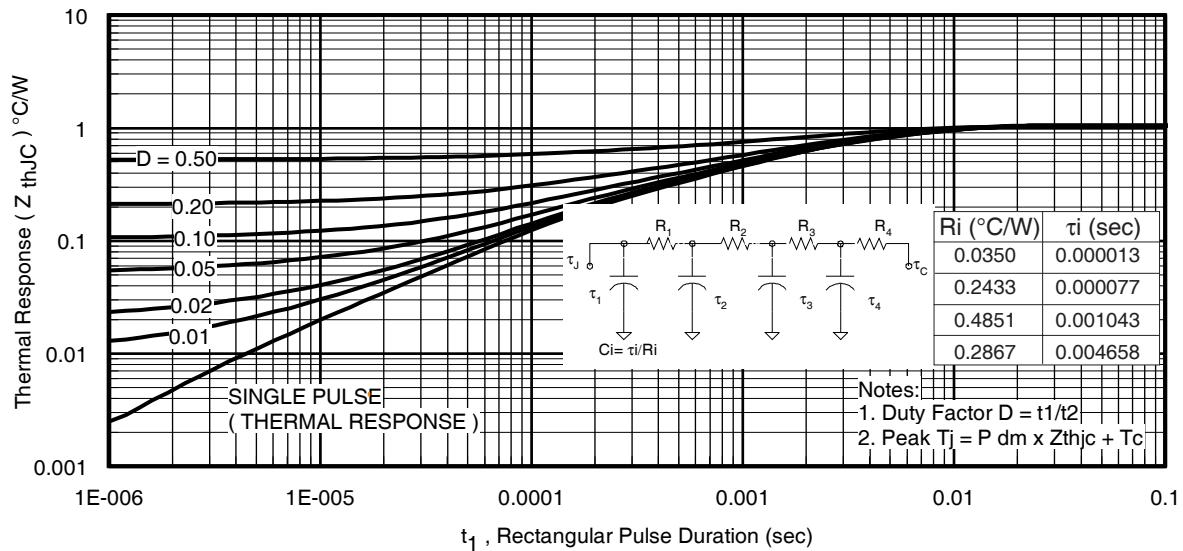


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

IRLR/U3114ZPbF

International
Rectifier

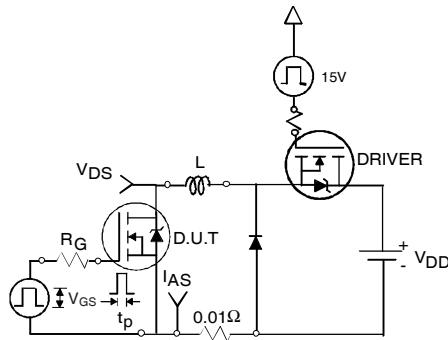


Fig 12a. Unclamped Inductive Test Circuit

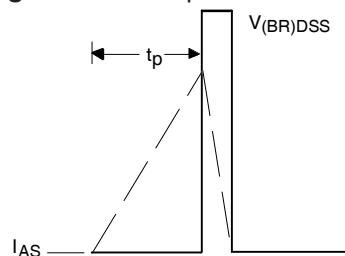


Fig 12b. Unclamped Inductive Waveforms

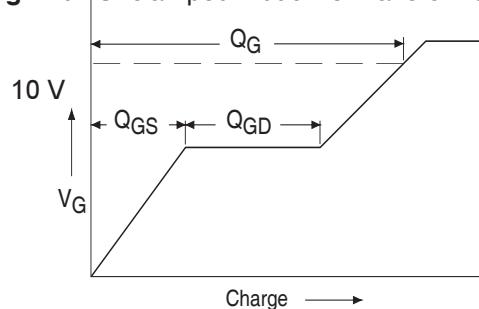


Fig 13a. Basic Gate Charge Waveform

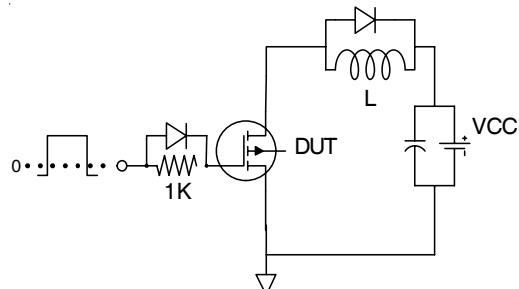


Fig 13b. Gate Charge Test Circuit

6

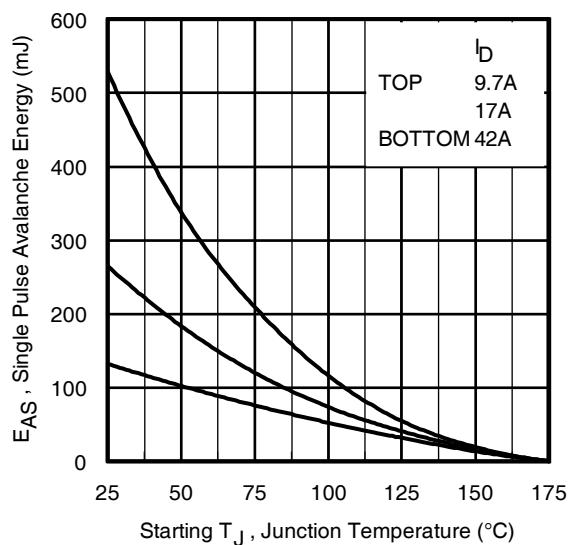


Fig 12c. Maximum Avalanche Energy vs. Drain Current

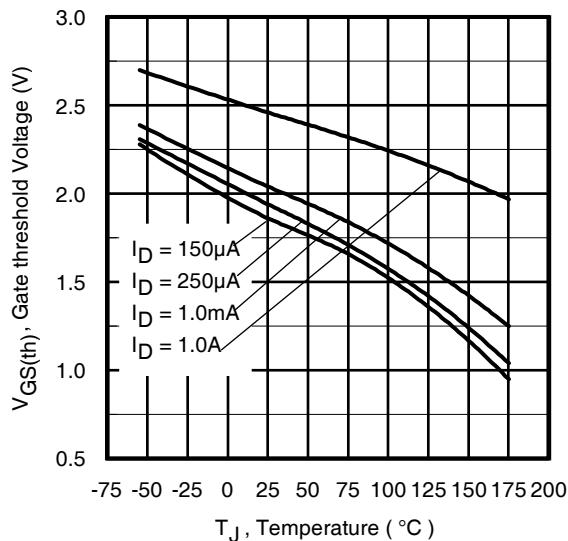


Fig 14. Threshold Voltage vs. Temperature

www.irf.com

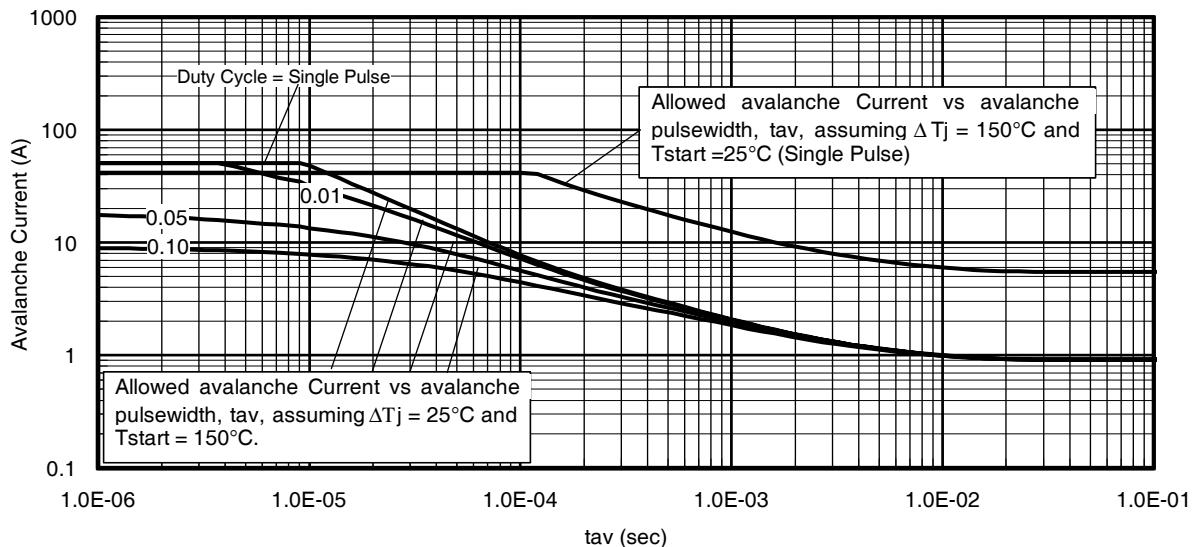


Fig 15. Typical Avalanche Current vs.Pulsewidth

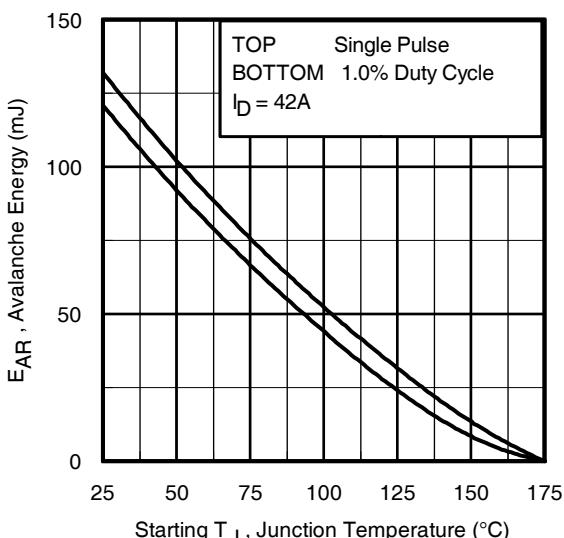


Fig 16. Maximum Avalanche Energy
vs. Temperature

**Notes on Repetitive Avalanche Curves , Figures 15, 16:
(For further info, see AN-1005 at www.irf.com)**

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as neither T_{jmax} nor I_{av} (max) is exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4. $P_{D(ave)}$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I_{av} = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
 t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{av} \cdot f$
 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

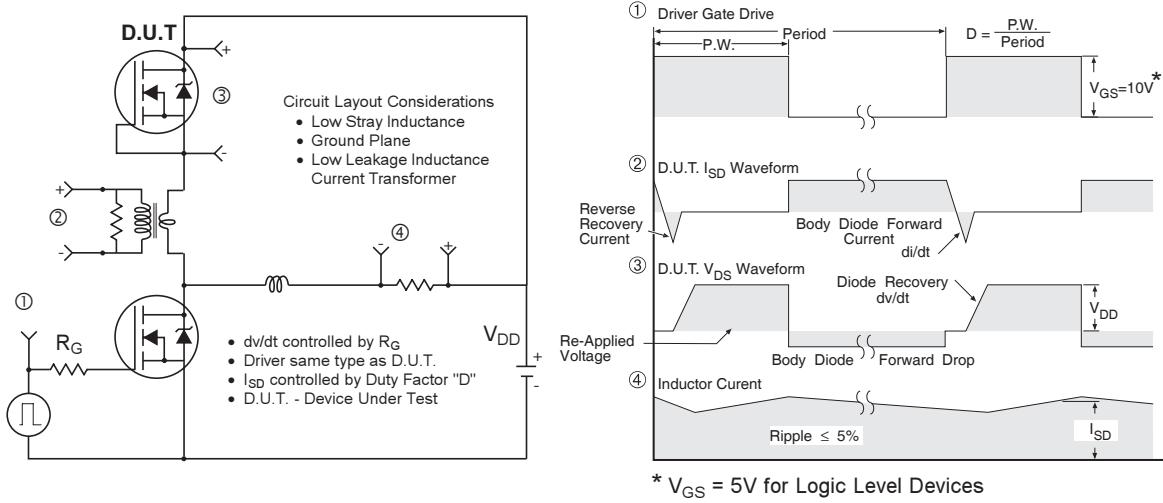


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

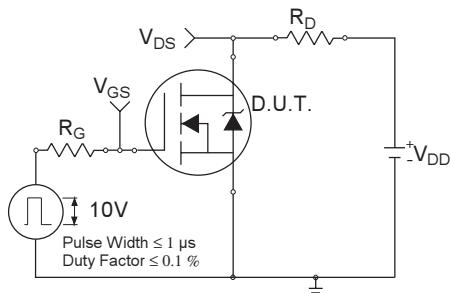


Fig 18a. Switching Time Test Circuit

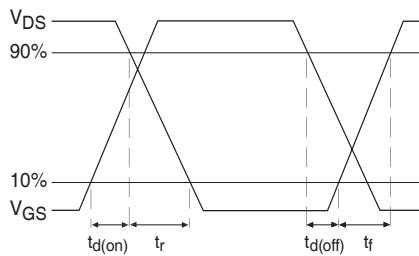


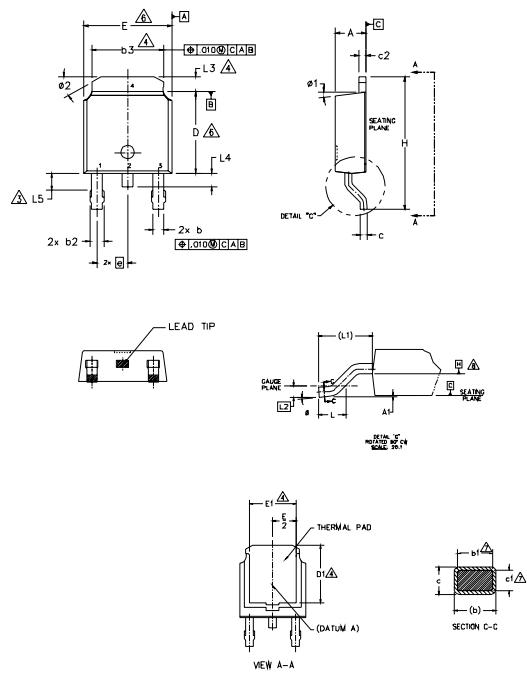
Fig 18b. Switching Time Waveforms

International
IR Rectifier

IRLR/U3114ZPbF

D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



DIMENSIONS	INCHES		NOTES
	MILLIMETERS	INCHES	
S	MIN.	MAX.	
A	2.18	2.39	.086 .094
A1	—	0.13	— .005
b	0.64	0.89	.025 .035
b1	0.65	0.79	.025 .031
b2	0.76	1.14	.030 .045
b3	4.95	5.46	.195 .215
c	0.46	0.61	.018 .024
c1	0.41	0.56	.016 .022
c2	0.46	0.89	.018 .035
D	5.97	6.22	.235 .245
D1	5.21	—	.205 —
E	6.35	6.73	.250 .265
E1	4.32	—	.170 —
e	2.29 BSC	.095 BSC	
H	9.40	10.41	.370 .410
L	1.40	1.78	.055 .070
L1	2.74 BSC	.108 REF.	
L2	0.51 BSC	.020 BSC	
L3	0.89	1.27	.035 .050
L4	—	1.02	— .040
L5	1.14	1.52	.045 .060
ø	0°	10°	0° 10°
ø1	0°	15°	0° 15°
ø2	25°	35°	25° 35°

LEAD ASSIGNMENTS

HEXFET

- GATE
- DRAIN
- SOURCE
- DRAIN

IGBT & CoPAK

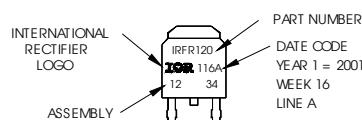
- GATE
- COLLECTOR
- Emitter
- COLLECTOR

D-Pak (TO-252AA) Part Marking Information

EXAMPLE: THIS IS AN IRFR120
WITH ASSEMBLY
LOT CODE 1234
ASSEMBLED ON WW 16, 2001
IN THE ASSEMBLY LINE "A"

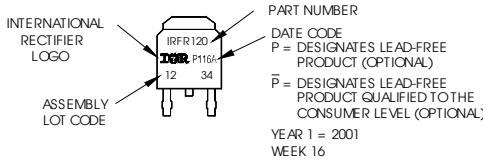
Note: "P" in assembly line position
indicates "Lead-Free"

"P" in assembly line position
indicates "Lead-Free" qualification to the consumer-level



PART NUMBER
DATE CODE
YEAR 1 = 2001
WEEK 16
LINE A

OR



PART NUMBER
DATE CODE
P = DESIGNATES LEAD-FREE
PRODUCT (OPTIONAL)
P = DESIGNATES LEAD-FREE
PRODUCT QUALIFIED TO THE
CONSUMER LEVEL (OPTIONAL)
YEAR 1 = 2001
WEEK 16
A = ASSEMBLY SITE CODE

Notes:

- For an Automotive Qualified version of this part please see <http://www.irf.com/product-info/auto/>
- For the most current drawing please refer to IR website at <http://www.irf.com/package/>

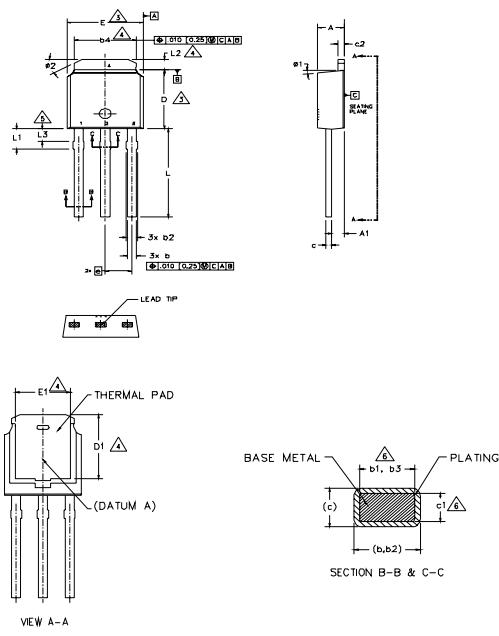
www.irf.com

IRLR/U3114ZPbF

International
IR Rectifier

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3.- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4.- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION b4, L2, E1 & D1.
- 5.- LEAD DIMENSION UNCONTROLLED IN L3.
- 6.- DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

SYMBOL	DIMENSIONS		NOTES
	MILLIMETERS	INCHES	
L	MIN.	MAX.	
A	2.18	.239	.086 .094
A1	0.89	1.14	.035 .045
b	0.64	0.89	.025 .035
b1	0.65	0.79	.025 .031
b2	0.76	1.14	.030 .045
b3	0.76	1.04	.030 .041
b4	4.95	5.46	.195 .215
c	0.46	0.61	.018 .024
c1	0.41	0.56	.016 .022
c2	0.46	0.89	.018 .035
D	5.97	6.22	.235 .245
D1	5.21	—	.205 —
E	6.35	6.73	.250 .265
E1	4.32	—	.170 —
e	2.29 BSC	—	.090 BSC
L	8.89	9.65	.350 .380
L1	1.91	2.29	.045 .090
L2	0.89	1.27	.035 .050
L3	1.14	1.52	.045 .060
Ø1	0"	15"	0" 15"
Ø2	25"	35"	25" 35"

LEAD ASSIGNMENTS

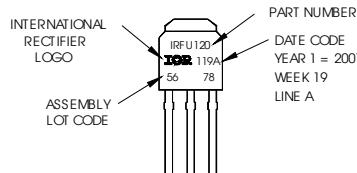
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

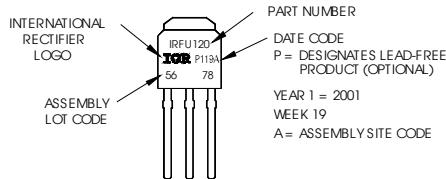
I-Pak (TO-251AA) Part Marking Information

EXAMPLE: THIS IS AN IRFU120
WTH ASSEMBLY
LOT CODE 5678
ASSEMBLED ON WW19, 2001
IN THE ASSEMBLY LINE "A"

Note: "P" in assembly line position
indicates Lead-Free™



OR



Notes:

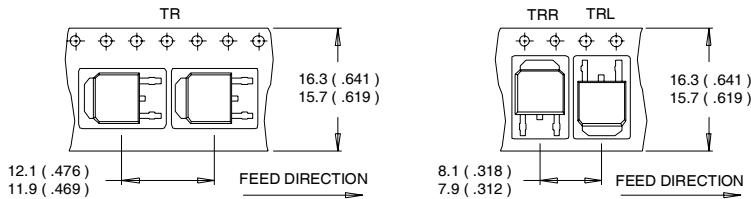
1. For an Automotive Qualified version of this part please see <http://www.irf.com/product-info/auto/>
2. For the most current drawing please refer to IR website at <http://www.irf.com/package/>

International
IR Rectifier

IRLR/U3114ZPbF

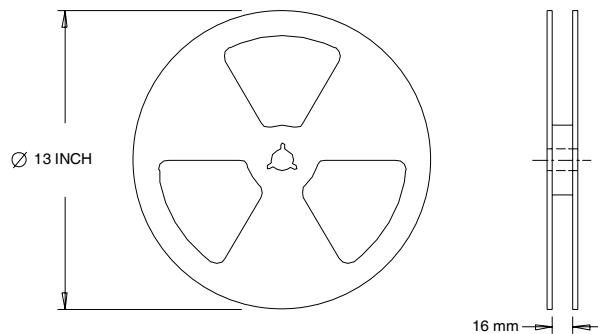
D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. OUTLINE CONFORMS TO EIA-481.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- ② Limited by T_{Jmax} , starting $T_J = 25^\circ\text{C}$, $L = 0.15\text{mH}$ $R_G = 25\Omega$, $I_{AS} = 42\text{A}$, $V_{GS} = 10\text{V}$. Part not recommended for use above this value.
- ③ Pulse width $\leq 1.0\text{ms}$; duty cycle $\leq 2\%$.
- ④ $C_{oss\ eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑤ Limited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population. 100% tested to this value in production.
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material).
- ⑧ R_θ is measured at T_J approximately 90°C .

Data and specifications subject to change without notice.
This product has been designed for the Industrial market.
Qualification Standards can be found on IR's Web site.

International
IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105
TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information.10/2010